

**Notice of References Cited**

Application/Control No.

10/738,403

Applicant(s)/Patent Under  
Reexamination  
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Examiner

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Art Unit

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**NON-PATENT DOCUMENTS**

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	V	Remondino Fabio, "3D Reconstruction of Articulated Objects from Uncalibrated Images," Jan. 2002, SPIE, Vol. 4661, pages 148-154
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.